•	Sea	arc	n	NC	)te	S		
		Ш	Ш	Ш			Ш	Ш

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/050,195	KANG ET AL.	
Examiner	Art Unit	
Junghwa M. Im	2811	

	SEAR	CHED	
Class	Subclass	Date	Examiner
257	767,768 769,770 295,753	8/1/2003	JMI
257	774	8/1/2003	JMI
above	updated	5/24/2006	JMI
			-

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST (uspat, uspub, epo, jpo, der, ibm)	5/24/2006	JMI		